Sear	ch Note	S

otes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/526,246	KAWAI ET AL.	
	Examiner	Art Unit	
	Noah Kamen	3747	

	SEARCHED			
Class	Subclass	Date	Examiner	
123	41.72	11/3/2005	18	
	41.74			
	41.79			
277	591			
	597			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see	EAST	11/3/2005	X
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SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
EAST	11/3/2005	NK.
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